

This Sheet Has Been Replaced



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ABSTRACT

An IC tester which is capable of conducting the test on analog devices or analog/digital mixed devices without being subject to the influence of any external noise is provided. A shielding case 100 is attached to a performance board 30 of a test head 13 and covers an IC socket 20 disposed in the test section of the handler 12 and at least that portion of the surface of the performance board to which the socket is mounted and an area adjoining the outer peripheral of that portion. The shielding case is formed through its top wall with an opening 102 through which a contact arm 91 with a pick-up head 92 may move into and out of the shielding case. An electrically conductive spring contact 103 surrounding the opening is attached to the shielding case, and an electrically conductive cover plate 104 is attached to the contact arm and positioned such that as the contact arm is lowered, the cover plate comes into contact with the spring contact to slightly press the latter.